

## 800V N-Channel Enhancement Mode MOSFET

### Description

The APJ12N80F/T/P is **CoolFET II** MOSFET family that is utilizing charge balance technology for extremely low on-resistance and low gate charge performance.

APJ12N80F/T/P is suitable for applications which require superior power density and outstanding efficiency

### General Features

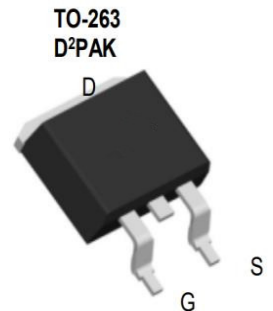
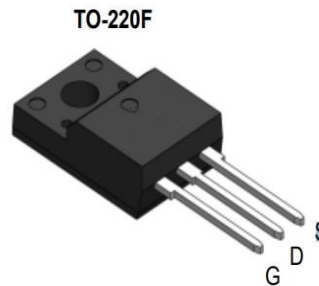
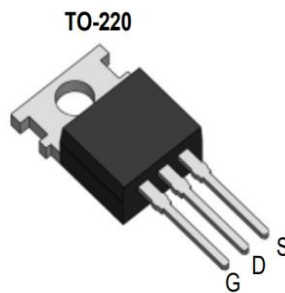
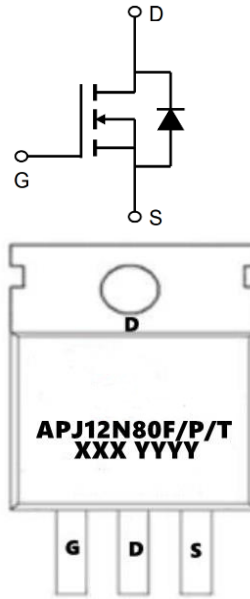
$V_{DS} = 800V$  (Type: 890V)  $IDM = 12A$

$R_{DS(ON)} < 900m\Omega$  @  $V_{GS} = 10V$  (Type: **800mΩ**)

### Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
APJ12N80F	TO-220F-3L	APJ12N80G XXX YYYY	1000
APJ12N80P	TO-220-3L	APJ12N80P XXX YYYY	1000
APJ12N80T	TO-263-3L	APJ12N80T XXX YYYY	800

### Absolute Maximum Ratings ( $T_c = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-Source Voltage ( $V_{GS} = 0V$ )	800	V
$I_D$	Continuous Drain Current	12	A
$I_{DM}$	Pulsed Drain Current (note1)	12	A
$V_{GS}$	Gate-Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulse Avalanche Energy (note2)	225	mJ
$P_D$	Power Dissipation ( $T_c = 25^\circ C$ )	25.5	W
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	$-55 \sim +150$	$^\circ C$
$R_{thJC}$	Thermal Resistance, Junction-to-Case	2	$^\circ C/W$
$R_{thJA}$	Thermal Resistance, Junction-to-Ambient	62.5	$^\circ C/W$



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**Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)**

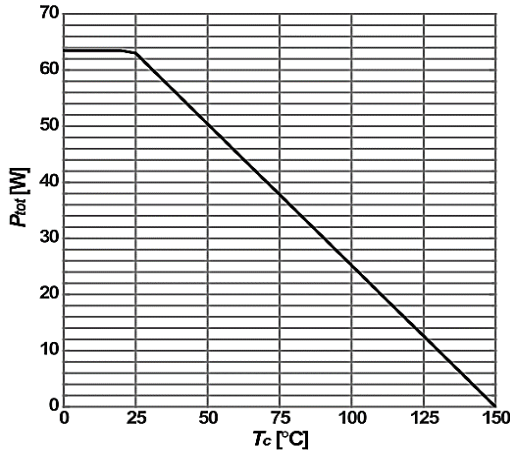
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-source breakdown voltage	VGS=0V, ID=250μA	800	-	-	V
V(GS)th	Gate threshold voltage	VDS=VGS, ID=250μA	2.5	3.5	4.5	V
IDSS	Zero gate voltage drain current	VDS=800V, VGS=0V, Tj=25°C	-	-	1	μA
IDSS	Zero gate voltage drain current	VDS=800V, VGS=0V, Tj=150°C	-	-	10	μA
IGSS	Gate-source leakage current	VGS=±30V, VDS=0V	-	-	±100	nA
RDS(on)	Drain-source on-state resistance	VGS=10V, ID=2.5A, Tj=25°C	-	800	900	mΩ
RDS(on)	Drain-source on-state resistance	VGS=10V, ID=2.5A, Tj=150°C	-	2000	5000	mΩ
Ciss	Input capacitance	VGS=0V, VDS=50V, f=1MHz	-	541	-	pF
Coss	Output capacitance		-	31.6	-	pF
Crss	Reverse transfer capacitance		-	1.33	-	pF
td(on)	Turn-on delay time	VDD=400V, VGS=13V, ID=2.2A,	-	17.6	-	ns
tr	Rise time		-	22.4	-	ns
td(off)	Turn-off delay time		-	64.2	-	ns
tf	Fall time		-	28.2	-	ns
Qgs	Gate to source charge	VDD=400V, ID=4A, VGS=0 to 10V	-	2.7	-	nC
Qgd	Gate to drain charge		-	4.97	-	nC
Qg	Gate charge total		-	10.7	-	nC
Vplateau	Gate plateau voltage		-	5.42	-	V
VSD	Diode forward voltage	VGS=0V, IF=5A, Tf=25°C	-	0.86	-	V
trr	Reverse recovery time	VR=400V, IF=1.1A, diF/dt=100A/μs	-	181	-	ns
Qrr	Reverse recovery charge		-	0.74	-	μC
Irrm	Peak reverse recovery current		-	8.68	-	A

**Note :**

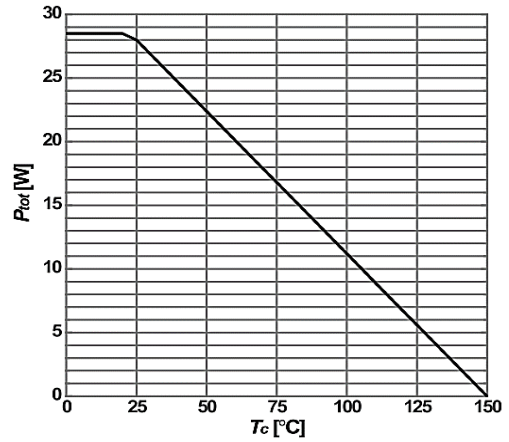
1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
2. The EAS data shows Max. rating . L=0.5mH, IAS =5.0A, VDD =50V, RG=25Ω
3. The test condition is Pulse Test: ISD ≤ ID, di/dt = 100A/us, VDD≤ BVDSS, Starting at TJ =25°C
4. The power dissipation is limited by 150°C junction temperature
5. The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

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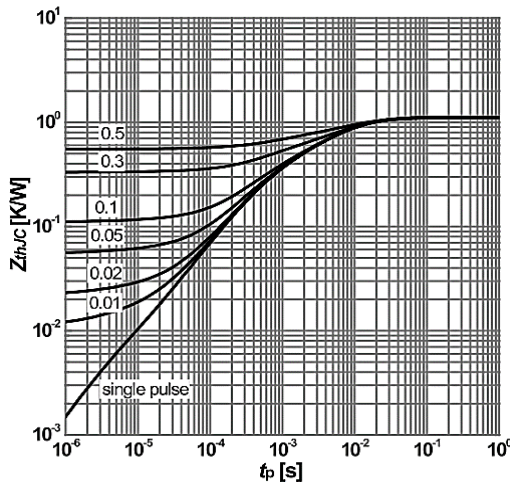
**Typical Characteristics**



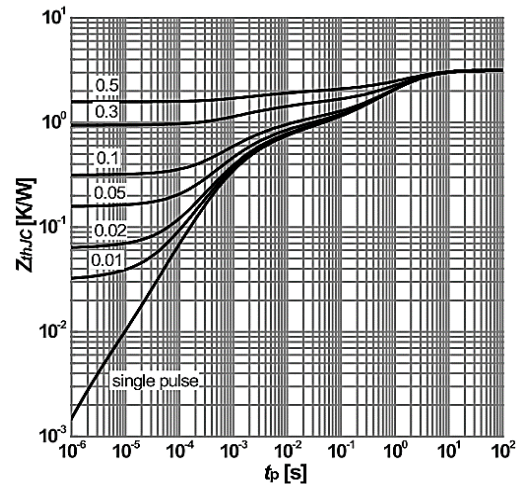
**Figure1: Power dissipation (Non FullPAK)**



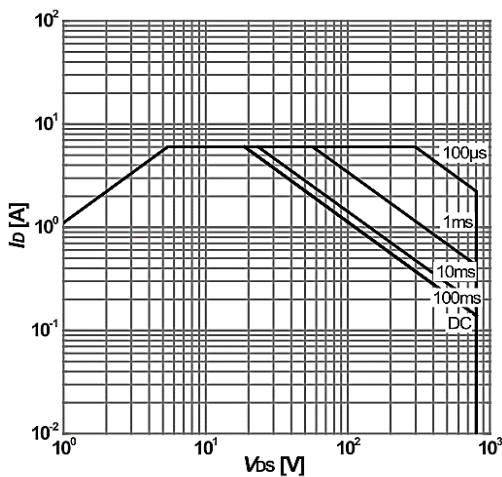
**Figure2: Power dissipation (FullPAK)**



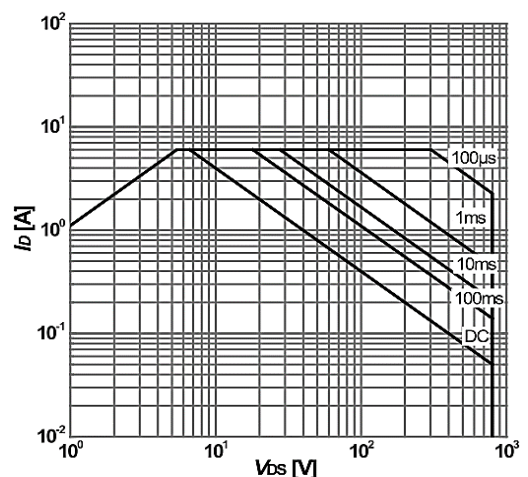
**Figure3:Max. transient thermal impedance**  
 $Z_{thJC}=f(t_p)$ ; parameter:  $D= t_p/T$



**Figure4:Max. transient thermal impedance**  
 $Z_{thJC}=f(t_p)$ ; parameter:  $D= t_p/T$

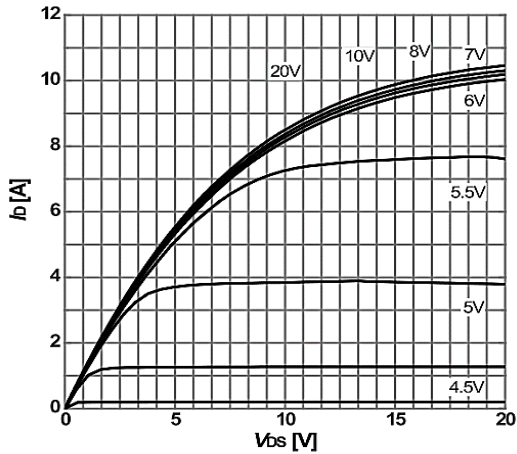


**Figure5: Safe operating area (Non FullPAK)**  
 $I_D=f(V_{DS})$ ;  $T_J=25^\circ\text{C}$ ;  $D=0$ ; parameter:  $t_p$



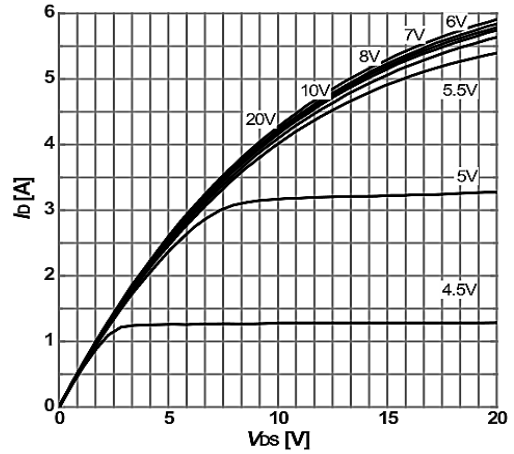
**Figure6: Safe operating area (FullPAK)**  
 $I_D=f(V_{DS})$ ;  $T_J=25^\circ\text{C}$ ;  $D=0$ ; parameter:  $t_p$

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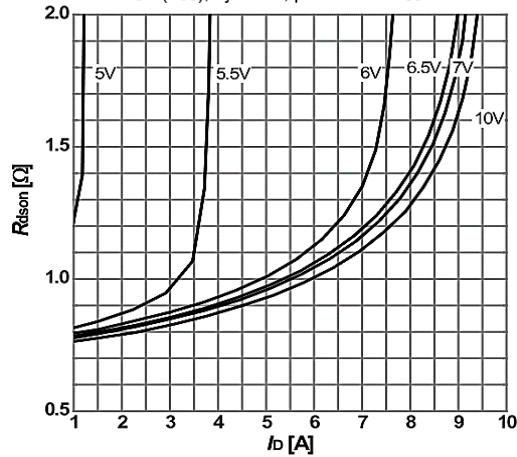
**Figure 7: Typ. output characteristics**

$I_D = f(V_{DS}); T_J = 25^\circ\text{C}; \text{parameter: } V_{GS}$



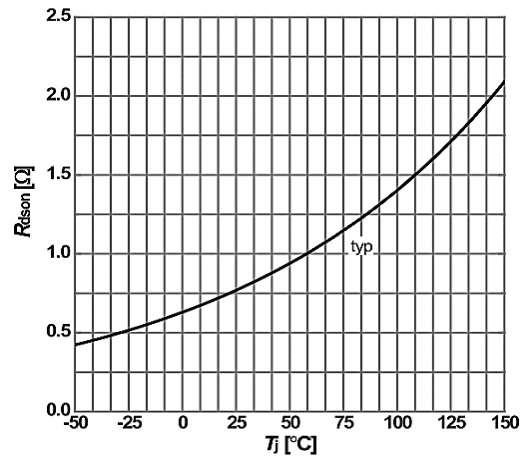
**Figure 8: Typ. output characteristics**

$I_D = f(V_{DS}); T_J = 125^\circ\text{C}; \text{parameter: } V_{GS}$



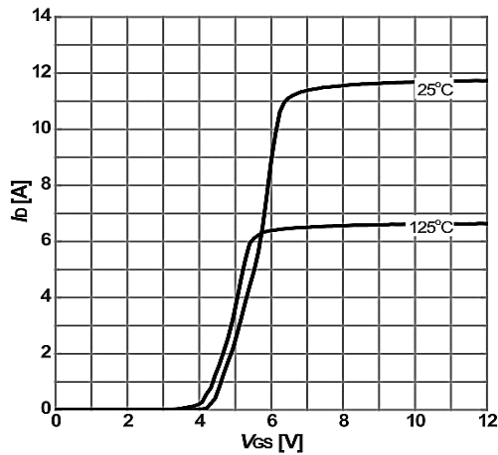
**Figure 9: Typ. drain-source on-state resistance**

$R_{DS(on)} = f(I_D); T_J = 25^\circ\text{C}; \text{parameter: } V_{GS}$



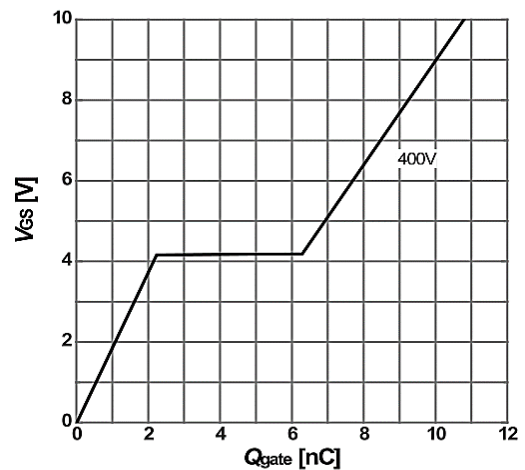
**Figure 10: drain-source on-state resistance**

$R_{DS(on)} = f(T_J); I_D = 3.2\text{A}; V_{GS} = 10\text{V}$



**Figure 11: Type. transfer characteristics**

$I_D = f(V_{GS}); V_{DS} = 20\text{V}; \text{parameter: } T_J$

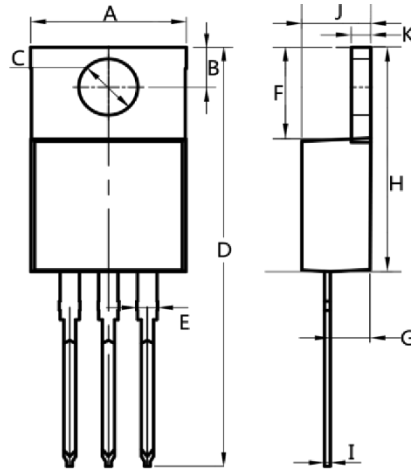


**Figure 12: Type. gate charge**

$V_{GS} = f(Q_{gate}); I_D = 3.2\text{A pulsed}; V_{DS} = 480\text{V}$

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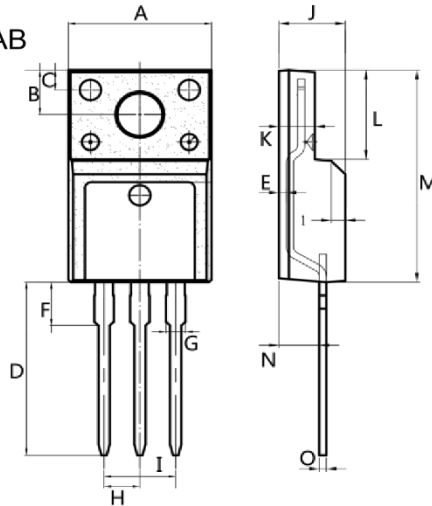
TO-220AB



Dim.	Min.	Max.
A	10.0	10.4
B	2.5	3.0
C	3.5	4.0
D	28.0	30.0
E	1.1	1.5
F	6.2	6.6
G	2.9	3.3
H	15.0	16.0
I	0.35	0.45
J	4.3	4.7
K	1.2	1.4

All Dimensions in millimeter

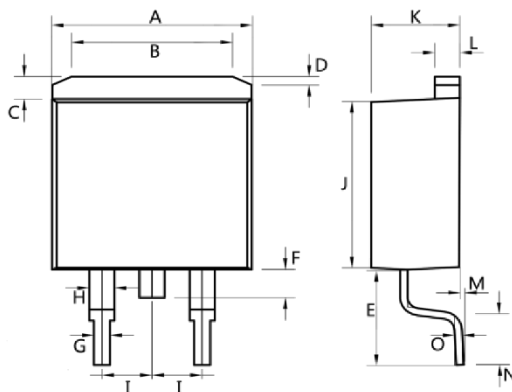
ITO-220AB



Dim.	Min.	Max.
A	9.9	10.3
B	2.9	3.5
C	1.15	1.45
D	12.75	13.25
E	0.55	0.75
F	3.1	3.5
G	1.25	1.45
H	Typ 2.54	
I	Typ 5.08	
J	4.55	4.75
K	2.4	2.7
L	6.35	6.75
M	15.0	16.0
N	2.75	3.15
O	0.45	0.60

All Dimensions in millimeter

TO-263



Dim.	Min.	Max.
A	10.0	10.5
B	7.25	7.75
C	1.3	1.5
D	0.55	0.75
E	5.0	6.0
F	1.4	1.6
G	0.75	0.95
H	1.15	1.35
I	Typ 2.54	
J	8.4	8.6
K	4.4	4.6
L	1.25	1.45
M	0.02	0.1
N	2.4	2.8
O	0.35	0.45

All Dimensions in millimeter